SIL DECLARATION OF CONFORMITY Model ST100 SERIES

We, Fluid Components International LLC, located at 1755 La Costa Meadows Drive, San Marcos, California 92078-5115 USA, declare as manufacturer, that the ST100 Series of products is suitable for use in a safety instrumented system for SIL 1, flow, temperature and pressure measurement.

The ST100 Series has been classified as Type B subsystem according to IEC 61508-1 Chapter 7.4.4.1.3 with a Hardware tolerance (HFT) of 0.

The Failure Modes, Effects and Diagnostic Analysis (FMEDA) report carried out by exida, resulted in following failure ratings:

SIL (Safety Integrity Level) : 1 - As a single device
HFT (Hardware Fault Tolerance) : 0
Subsystem type : B

Failure rates according to IEC 61508-1

<table>
<thead>
<tr>
<th>Function</th>
<th>SFF</th>
<th>PFD (AVG)</th>
<th>λDU</th>
<th>λDD</th>
<th>λSU</th>
<th>λSD</th>
</tr>
</thead>
<tbody>
<tr>
<td>Single Probe AC supply</td>
<td>79.8%</td>
<td>1.21 x 10^-2</td>
<td>567 FIT</td>
<td>1927 FIT</td>
<td>314 FIT</td>
<td>0</td>
</tr>
<tr>
<td>Single Probe DC supply</td>
<td>79.9%</td>
<td>1.22 x 10^-2</td>
<td>570 FIT</td>
<td>1946 FIT</td>
<td>317 FIT</td>
<td>0</td>
</tr>
<tr>
<td>Dual Probe AC supply</td>
<td>88.9%</td>
<td>1.00 x 10^-2</td>
<td>415 FIT</td>
<td>2918 FIT</td>
<td>404 FIT</td>
<td>0</td>
</tr>
<tr>
<td>Dual Probe DC supply</td>
<td>88.9%</td>
<td>1.01 x 10^-2</td>
<td>418 FIT</td>
<td>2937 FIT</td>
<td>407 FIT</td>
<td>0</td>
</tr>
</tbody>
</table>

Terminology:
SFF = Safe Failure fraction
PFD = Probability of failure on demand
λDU = failure rate dangerous undetected faults
λDD = failure rate dangerous detected faults
λSU = failure rate safe undetected faults
λSD = failure rate safe detected faults
FIT = Failure Rate in 10^-9/hour

Above analysis is based on assuming:
- The HART protocol is used for setup, calibration and diagnostics purposes, not for safety critical function.
- Materials are compatible with process conditions.
- The device is installed per manufacturer’s instructions.
- External power supply failure rates are not included.
- Worst-case internal fault detection time is 1 hour.
- The device is configured for fault detection per NAMUR NE43 or the logic solver is configured to interpret output fault conditions.
- Proof test interval of 1 year.

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Eric Wible, Engineering Manager